# Notice of References Cited 10/786,343 Reexamination NASH, MICHAEL TEPOE Examiner Christina Russell Reexamination NASH, MICHAEL TEPOE Art Unit Page 1 of 3

Application/Control No.

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Dåte MM-YYYY	Name	Classification
*	Α	US-5,408,914	04-1995	Breitweiser et al.	84/477R
*	В	US-2003/0110926	06-2003	Sitrick et al.	84/477.00R
*	С	US-5,837,912	11-1998	Eagen, Chris S.	84/267
*	D	US-6,191,348	02-2001	Johnson, Steven T.	. 84/485R
*	Е	US-5,837,912	11-1998	Eagen, Chris S.	84/267
*	Е	US-6,191,350	02-2001	Okulov et al.	84/646
*	G	US-5,442,986	08-1995	Cota, Jose G.	84/267
*	Н	US-6,291,755	09-2001	Hine et al.	84/454
*	Т	US-6,350,942	02-2002	Thomson, Richard Atwater	84/477R
*	J	US-4,080,867	03-1978	Ratanangsu, Srinkarn	84/477R
*	К	US-4,919,031	04-1990	Matsumoto, Naoaki	84/601
*	L	US-6,888,057	05-2005	Juszkiewicz et al.	84/645
*	М	US-6,253,654	07-2001	Mercurio, Peter G	84/267

# FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	· · Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	α					
	R					
	S					
	Т					

#### **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	`
,	٧	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under

# Notice of References Cited Application/Control No. 10/786,343 Applicant(s)/Patent Under Reexamination NASH, MICHAEL TEPOE Examiner Christina Russell Art Unit Page 2 of 3

# U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,452,081	09-2002	Ravagni et al.	. 84/477R
*	В	US-6,645,067	11-2003	Okita et al.	463/7
*	С	US-6,653,543	11-2003	Kulas, Charles J.	84/454
*	D	US-6,995,310	02-2006	Knapp et al.	84/722
*	E	US-5,038,662	08-1991	Ho, Tracy K.	84/723
*	F	US-6,162,981	12-2000	Newcomer et al.	84/485R
*	G	US-5,977,467	11-1999	Freeland et al.	84/454
*	Н	US-4,378,720	04-1983	Nakada et al.	84/611
*	1	US-5,270,475	12-1993	Weiss et al.	84/603
*	J	US-5,266,735	11-1993	Shaffer et al.	84/609
*	к	US-5,040,447	08-1991	Murata et al.	84/612
*	L	US-4,791,848	12-1988	Blum, Jr., Kenneth L.	84/453
*	М	US-4,318,327	03-1982	Toups, Daniel J.	84/477R

# FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р	O				
	Q					
	R				,	
	S					
	Т					

### **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination NASH, MICHAEL TEPOE | Examiner | Art Unit | Page 3 of 3

# U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,889,221	03-1999	Dejima, Tatsuya	84/291
*	В	US-2005/0252359	11-2005	Cook, Randy Mitchell	084/464.00A
*	С	US-6,787,690	09-2004	Celi et al.	84/723
*	D	US-6,065,765	05-2000	Chang, Richard M.	280/288.3
*	E	US-4,658,690	04-1987	Aitken et al.	84/629
	E	US-			
	G	US-			
	н	US-			
	1	US-			
	J	US-			
	Κ.	US-			
	L	US-			
	М	US-			•

# FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q.					
	R					
	s					
	Т					

# **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.